

Features

- Any frequency between 1 MHz and 110 MHz accurate to 6 decimal places
- 100% pin-to-pin drop-in replacement to quartz-based XO
- Excellent total frequency stability as low as ±25 PPM
- Industry best G-sensitivity of 0.1 PPB/G
- Low power consumption of 3.6 mA typical
- LVCMOS/HCMOS compatible output
- Industry-standard packages: 2.0 x 1.6, 2.5 x 2.0, 3.2 x 2.5, 5.0 x 3.2, 7.0 x 5.0 mm
- Pb-free, RoHS and REACH compliant
- Optional unique device ID for complete traceability (contact SiTime)
- Optional AECQ100 compliance (contact SiTime)

Electrical Characteristics^[1, 2]

Applications

- Automotive, medical, industrial and other high reliability electronics
- Infotainment systems, industrial sensors, collision detection devices, equipment control boards, etc.



Parameter and Conditions	Symbol	Min.	Тур.	Max.	Unit	Condition
			F	requency R	ange	
Output Frequency Range	f	1	-	110	MHz	
			Frequer	cy Stability	and Aging	
Frequency Stability	F_stab	-25	-	+25	PPM	Inclusive of Initial tolerance at 25°C, and variations over
		-50	-	+50	PPM	operating temperature, rated power supply voltage and load.
Aging	Ag	-1.5	-	1.5	PPM	1st year at 25°C
Operating Temperature Range	T_use	-40	-	-105	°C	Extended Industrial
		-40	-	+125	°C	Automotive
			Operati	ng Tempera	ture Range	
Supply Voltage	Vdd	1.62	1.8	1.98	V	Contact SiTime for 1.5V support
		2.25	2.5	2.75	V	
		2.52	2.8	3.08	V	
		2.7	3.0	3.3	V	
		2.97	3.3	3.63	V	
		2.25	-	3.63	V	
Current Consumption	Idd – 3.9 5 mA No load condition, f = 2		No load condition, f = 20 MHz, Vdd = 2.5V, 2.8V, 3.0V or $3.3V$			
		Ι	3.6	4.5	mA	No load condition, f = 20 MHz, Vdd = 1.8V
Standby Current	I_std	-	2.5	10	μA	ST = GND, Vdd = 3.0V or 3.3V, Output is Weakly Pulled Down
		-	2.5	10	μΑ	ST = GND, Vdd = 2.5V or 2.8V, Output is Weakly Pulled Down
		-	1	5	μA	ST = GND, Vdd = 1.8V, Output is Weakly Pulled Down
			LVCMOS	Output Ch	aracteristic	S
Duty Cycle	DC	45	-	55	%	All Vdds
Rise/Fall Time	Tr, Tf	-	1.2	2.5	ns	Vdd = 2.5V, 2.8V, 3.0V or 3.3V, 20% - 80%
		-	1.5	3.5	ns	Vdd =1.8V, 20% - 80%
		-	1.5	3	ns	Vdd = 2.25V - 3.63V, 20% - 80%
Output High Voltage	VOH	90%	-	-	Vdd	IOH = -4 mA (Vdd = 3.0V or 3.3V) IOH = -3 mA (Vdd = 2.8V and Vdd = 2.5V) IOH = -2 mA (Vdd = 1.8V)
Output Low Voltage	VOL	_	-	10%	Vdd	IOL = 4 mA (Vdd = 3.0V or 3.3V) IOL = 3 mA (Vdd = 2.8V and Vdd = 2.5V) IOL = 2 mA (Vdd = 1.8V)
			Inp	ut Characte	ristics	
Input High Voltage	VIH	70%	-	-	Vdd	Pin 1, OE or ST
Input Low Voltage	VIL	-	-	30%	Vdd	Pin 1, OE or ST
Input Pull-up Impedence	Z_in	_	100	250	kΩ	Pin 1, OE logic high or logic low, or ST logic high
		2	-	_	MΩ	Pin 1, ST logic low

Notes:

1. All electrical specifications in the above table are specified with 15 pF output load and for all Vdd(s) unless otherwise stated.

2. Contact SiTime for custom drive strength to drive higher or multiple load, or SoftEdge™ option for EMI reduction.

Rev. 0.92



Electrical Characteristics^[1, 2] (continued)

		•				
Parameter and Conditions	Symbol	Min.	Тур.	Max.	Unit	Condition
			Startu	o and Resu	me Timing	
Startup Time	T_start	-	-	5	ms	Measured from the time Vdd reaches its rated minimum value
Enable/Disable Time	T_oe	-	-	150	ns	
Resume Time	T_resume	-	-	5	ms	Measured from the time ST pin crosses 50% threshold
				Jitter	•	·
RMS Period Jitter	T_jitt	-	2	4	ps	f = 20 MHz, Vdd = 2.5V, 2.8V, 3.0V or 3.3V
		-	2	4.5	ps	f = 20 MHz, Vdd = 1.8V
RMS Phase Jitter (random)	T_phj	-	0.7	1	ps	Integration bandwidth = 900 kHz to 7.5 MHz
		-	1.5	3	ps	Integration bandwidth = 12 kHz to 20 MHz

Notes:

1. All electrical specifications in the above table are specified with 15 pF output load and for all Vdd(s) unless otherwise stated.

2. Contact SiTime for custom drive strength to drive higher or multiple load, or SoftEdge™ option for EMI reduction.

Pin Description

	Pin	Symbol		Functionality		Top View	
Γ			Output Enable	H or Open ^[3] : specified frequency output L: output is high impedance. Only output driver is disabled.			
	1 OE/ ST Sta	Standby	H or Open ^[3] : specified frequency output L: output is low (weak pull down). Device goes to sleep mode. Supply current reduces to I_std.	OE/ST	1 4 V	+ VDD	
	2	GND	Power	Electrical ground ^[4]			
	3	OUT	Output	Oscillator output	GND	2 3	3 OUT
	4	VDD	Power	Power supply voltage ^[4]			

Note:

3. A pull-up resistor of <10 k Ω between OE/ \overline{ST} pin and Vdd is recommended in high noise environment.

4. A capacitor of value 0.1 μF between Vdd and GND is recommended.

Absolute Maximum

Attempted operation outside the absolute maximum ratings of the part may cause permanent damage to the part. Actual performance of the IC is only guaranteed within the operational specifications, not at absolute maximum ratings.

Parameter	Min.	Max.	Unit
Storage Temperature	-65	150	°C
VDD	-0.5	4	V
Electrostatic Discharge	-	2000	V
Soldering Temperature (follow standard Pb free soldering guidelines)	-	260	°C
Junction Temperature	-	150	°C

Thermal Consideration

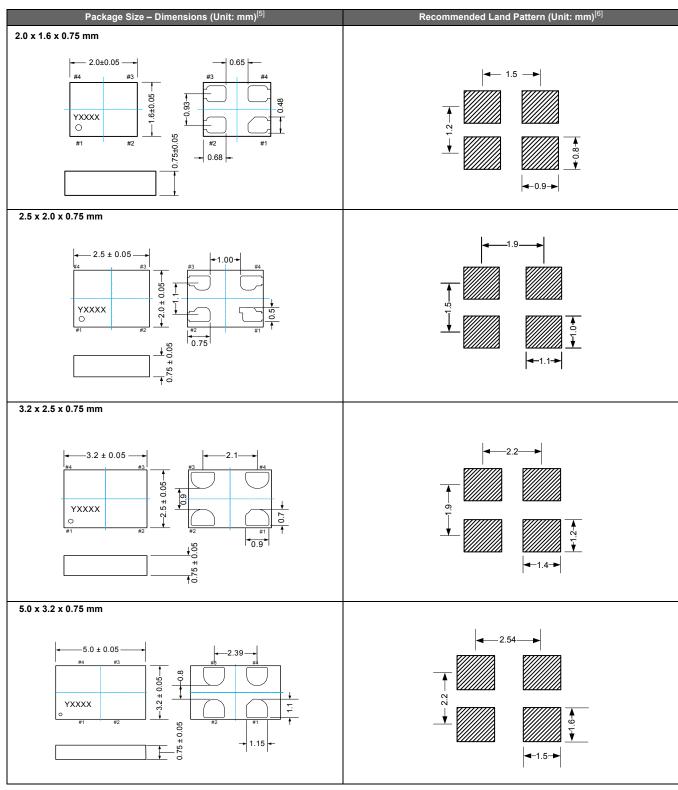
Package	θJA, 4 Layer Board (°C/W)	θJA, 2 Layer Board (°C/W)	θJC, Bottom (°C/W)
7050	191	263	30
5032	97	199	24
3225	109	212	27
2520	117	222	26
2016	124	227	26

Environmental Compliance

Parameter	Condition/Test Method
Mechanical Shock	MIL-STD-883F, Method 2002
Mechanical Vibration	MIL-STD-883F, Method 2007
Temperature Cycle	JESD22, Method A104
Solderability	MIL-STD-883F, Method 2003
Moisture Sensitivity Level	MSL1 @ 260°C



Dimensions and Patterns

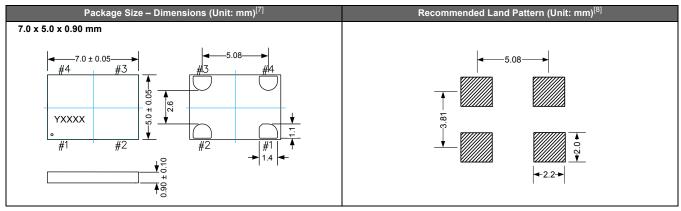


Notes:

Top marking: Y denotes manufacturing origin and XXXX denotes manufacturing lot number. The value of "Y" will depend on the assembly location of the device.
 A capacitor of value 0.1 µF between Vdd and GND is recommended.



Dimensions and Patterns



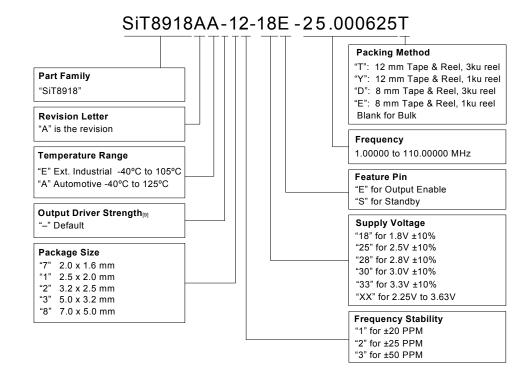
Notes:

- 7. Top marking: Y denotes manufacturing origin and XXXX denotes manufacturing lot number. The value of "Y" will depend on the assembly location of the device.
- 8. A capacitor of value 0.1 μF between Vdd and GND is recommended.

SiT8918 High Temperature Oscillator



Ordering Information



Note:

9. Contact SiTime for custom drive strength to drive higher or multiple load, or SoftEdge™ option for EMI reduction.

Ordering Codes for Supported Tape & Reel Packing Method^[10]

Device Size	12 mm T&R (3ku)	12 mm T&R (1ku)	8 mm T&R (3ku)	8 mm T&R (1ku)
2.0 x 1.6 mm	-	-	D	E
2.5 x 2.0 mm	-	-	D	E
3.2 x 2.5 mm	-	-	D	E
5.0 x 3.2 mm	Т	Y	-	-
7.0 x 5.0 mm	Т	Y	-	-

Note:

10.For "--", contact SiTime for availability.

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Supplemental Information

The Supplemental Information section is not part of the datasheet and is for informational purposes only.



Silicon MEMS Outperforms Quartz



Best Reliability

Silicon is inherently more reliable than quartz. Unlike quartz suppliers, SiTime has in-house MEMS and analog CMOS expertise, which allows SiTime to develop the most reliable products. Figure 1 shows a comparison with quartz technology.

Why is SiTime Best in Class:

- SiTime's MEMS resonators are vacuum sealed using an advanced Epi-Seal[™] process, which eliminates foreign particles and improves long term aging and reliability
- · World-class MEMS and CMOS design expertise

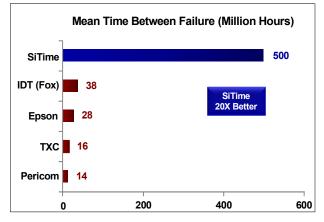


Figure 1. Reliability Comparison^[1]

Best Aging

Unlike quartz, MEMS oscillators have excellent long term aging performance which is why every new SiTime product specifies 10-year aging. A comparison is shown in Figure 2.

Why is SiTime Best in Class:

- SiTime's MEMS resonators are vacuum sealed using an advanced Epi-Seal[™] process, which eliminates foreign particles and improves long term aging and reliability
- Inherently better immunity of electrostatically driven MEMS resonator

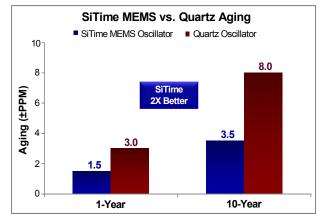


Figure 2. Aging Comparison^[2]

Best Electro Magnetic Susceptibility (EMS)

SiTime's oscillators in plastic packages are up to 54 times more immune to external electromagnetic fields than quartz oscillators as shown in Figure 3.

Why is SiTime Best in Class:

- Internal differential architecture for best common mode noise rejection
- Electrostatically driven MEMS resonator is more immune to EMS

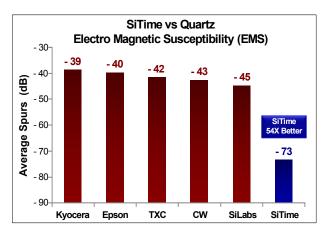


Figure 3. Electro Magnetic Susceptibility (EMS)^[3]

Best Power Supply Noise Rejection

SiTime's MEMS oscillators are more resilient against noise on the power supply. A comparison is shown in Figure 4.

Why is SiTime Best in Class:

- On-chip regulators and internal differential architecture for common mode noise rejection
- · Best analog CMOS design expertise

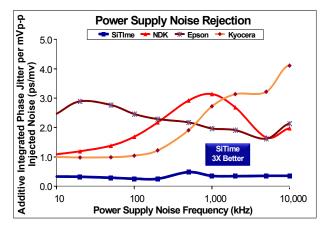


Figure 4. Power Supply Noise Rejection^[4]



Best Vibration Robustness

High-vibration environments are all around us. All electronics, from handheld devices to enterprise servers and storage systems are subject to vibration. Figure 5 shows a comparison of vibration robustness.

Why is SiTime Best in Class:

- The moving mass of SiTime's MEMS resonators is up to 3000 times smaller than quartz
- Center-anchored MEMS resonator is the most robust design

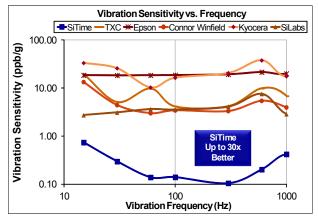


Figure 5. Vibration Robustness^[5]

Notes:

- 1. Data Source: Reliability documents of named companies.
- 2. Data source: SiTime and quartz oscillator devices datasheets.
- 3. Test conditions for Electro Magnetic Susceptibility (EMS):
 - According to IEC EN61000-4.3 (Electromagnetic compatibility standard)
 Eicle stage stage
 - Field strength: 3V/m
 - Radiated signal modulation: AM 1 kHz at 80% depth
 - Carrier frequency scan: 80 MHz 1 GHz in 1% steps
 - Antenna polarization: Vertical
 - · DUT position: Center aligned to antenna

Devices used in this test:

SiTime, SiT9120AC-1D2-33E156.250000 - MEMS based - 156.25 MHz Epson, EG-2102CA 156.2500M-PHPAL3 - SAW based - 156.25 MHz TXC, BB-156.250MBE-T - 3rd Overtone quartz based - 156.25 MHz Kyocera, KC7050T156.250P30E00 - SAW based - 156.25 MHz Connor Winfield (CW), P123-156.25M - 3rd overtone quartz based - 156.25 MHz SiLabs, Si590AB-BDG - 3rd overtone quartz based - 156.25 MHz

4. 50 mV pk-pk Sinusoidal voltage.

Devices used in this test:

SiTime, SiT8208AI-33-33E-25.000000, MEMS based - 25 MHz NDK, NZ2523SB-25.6M - quartz based - 25.6 MHz

- NDR, NZ25253B-25.0M Qualtz based 25.0 MHz
- Kyocera, KC2016B25M0C1GE00 quartz based 25 MHz Epson, SG-310SCF-25M0-MB3 - guartz based - 25 MHz
- Devices used in this test: same as EMS test stated in Note 3.
- 6. Test conditions for shock test:
- MIL-STD-883F Method 2002
- Condition A: half sine wave shock pulse, 500-g, 1ms
- Continuous frequency measurement in 100 µs gate time for 10 seconds
- Devices used in this test: same as EMS test stated in Note 3

7. Additional data, including setup and detailed results, is available upon request to qualified customers. Please contact productsupport@sitime.com.

Best Shock Robustness

SiTime's oscillators can withstand at least 50,000 g shock. They all maintain their electrical performance in operation during shock events. A comparison with quartz devices is shown in Figure 6.

Why is SiTime Best in Class:

- The moving mass of SiTime's MEMS resonators is up to 3000 times smaller than quartz
- Center-anchored MEMS resonator is the most robust design

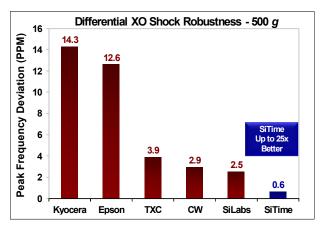


Figure 6. Shock Robustness^[6]

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